TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSIII)

# **TPCS8302**

Lithium Ion Battery Applications
Notebook PC Applications
Portable Machines and Tools

- Small footprint due to small and thin package
- Low drain-source ON resistance: RDS (ON) = 22 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 12 S$  (typ.)
- Low leakage current:  $I_{DSS} = -10 \mu A \text{ (max) (V}_{DS} = -20 \text{ V)}$
- Enhancement-mode:  $V_{th} = -0.5 \sim -1.2 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -200 \text{ }\mu\text{A})$

### Maximum Ratings (Ta = 25°C)

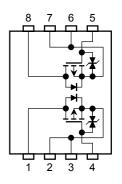
Char	acteristics	Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	-20	V	
Drain-gate voltag	ge (R <sub>GS</sub> = 20 kΩ)	$V_{DGR}$	-20	V	
Gate-source volt	Gate-source voltage		±12	V	
Drain current	DC (Note 1)	I <sub>D</sub>	-5	А	
Diaili Cuileiil	Pulse (Note 1)	I <sub>DP</sub>	-20 -20 ±12	A	
Drain power	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.1		
dissipation (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.75	W	
Drain power dissipation (t = 10 s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.6		
	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.35	W	
Single pulse avalanche energy (Note 4)		E <sub>AS</sub>	32.5	mJ	
Avalanche curre	Avalanche current		-5	Α	
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		E <sub>AR</sub>	0.075	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

2-3R1E

Weight: 0.035 g (typ.)

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# **Circuit Configuration**



Note: (Note 1), (Note 2), (Note 3), (Note 4), (Note 5), please see next page.

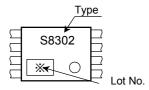
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This transistor is an electrostatic sensitive device. Please handle with caution.

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit		
The second resistance of the second to exclude	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	114	°C/W	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	167		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	208		
(t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	357	°C/W	

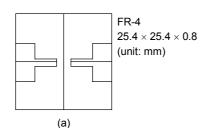
### Marking (Note 6)



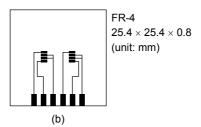
Note 1: Please use devices on condition that the channel temperature is below 150°C.

#### Note 2:

a) Device mounted on a glass-epoxy board (a)

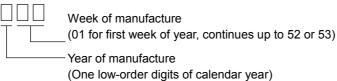


b) Device mounted on a glass-epoxy board (b)



#### Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)
- Note 4:  $V_{DD} = -16 \text{ V}$ ,  $T_{Ch} = 25^{\circ}\text{C}$ , L = 1.0 mH,  $I_{AR} = -5 \text{ A}$ ,  $R_G = 25 \Omega$
- Note 5: Repetitive rating: pulse width limited by max channel temperature
- Note 6:  $\circ$  on lower right of the marking indicates Pin 1.
  - Weekly code: (Three digits)



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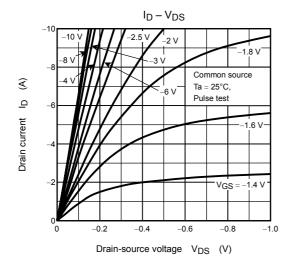
# Electrical Characteristics (Ta = 25°C)

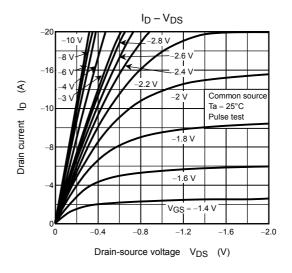
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-OFF cu	ırrent	I <sub>DSS</sub>	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$			μΑ	
Drain-source bre	akdown voltage	V <sub>(BR)DSS</sub>	$I_D = -10$ mA, $V_{GS} = 0$ V	-20	_		V
Drain-source bre	akdown voltage	V <sub>(BR) DSX</sub>	$I_D = -10 \text{ mA}, V_{GS} = 12 \text{ V}$	-8	_		v
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, I_D = -200 \mu\text{A}$	-0.5	_	-1.2	V
			$V_{GS} = -2.0 \text{ V}, I_D = -2.5 \text{ A}$		42	95	mΩ
Drain-source ON	resistance	R <sub>DS</sub> (ON)	$V_{GS} = -2.5 \text{ V}, I_D = -2.5 \text{ A}$		32	60	
			$V_{GS} = -4.5 \text{ V}, I_D = -2.5 \text{ A}$	_	22	35	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -2.5 \text{ A}$	5.5	12	_	S
Input capacitance		C <sub>iss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	1590	_	pF
Reverse transfer capacitance		C <sub>rss</sub>		_	380	_	
Output capacitance		C <sub>oss</sub>		_	430	_	
Switching time	Rise time	t <sub>r</sub>	V <sub>GS</sub> -5 V   I <sub>D</sub> = -2.5 A   C   C   C   C   C   C   C   C   C		9		- ns
	Turn-ON time	t <sub>on</sub>			16		
	Fall time	t <sub>f</sub>			45	1	
	Turn-OFF time	t <sub>off</sub>	$V_{DD} \simeq 10 \text{ V}$ Duty $\leq$ 1%, $t_W = 10 \mu\text{s}$		113		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \approx 16 \text{ V}, V_{GS} = -5 \text{ V}, I_D = -5 \text{ A}$		28.5	_	
Gate-source charge 1		Q <sub>gs</sub>		_	19	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	9.4	_	

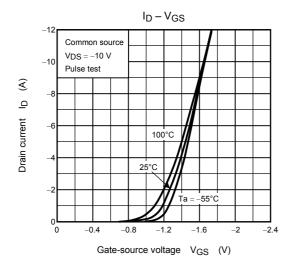
## **Source-Drain Ratings and Characteristics (Ta = 25°C)**

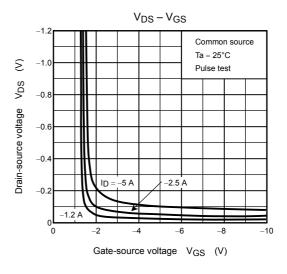
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	-20	Α
Forward voltage (diode)		$V_{DSF}$	$I_{DR} = -5 A$ , $V_{GS} = 0 V$		_	1.2	V

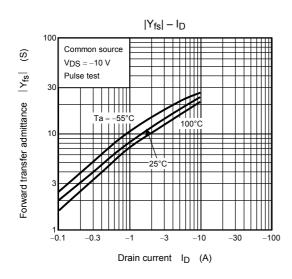
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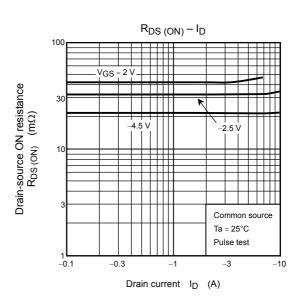


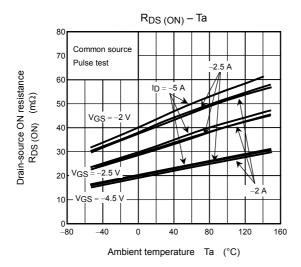


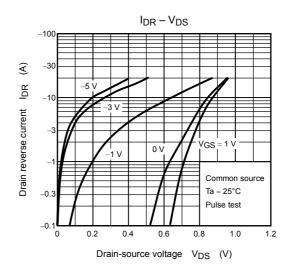


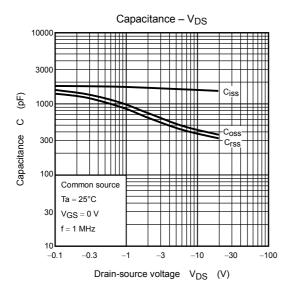


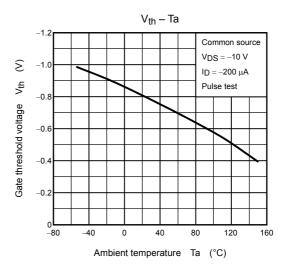


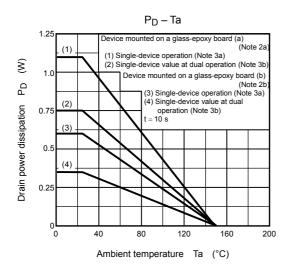


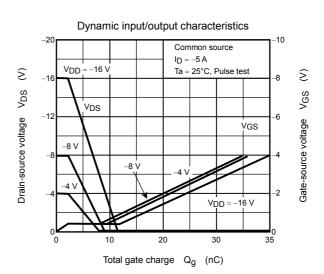


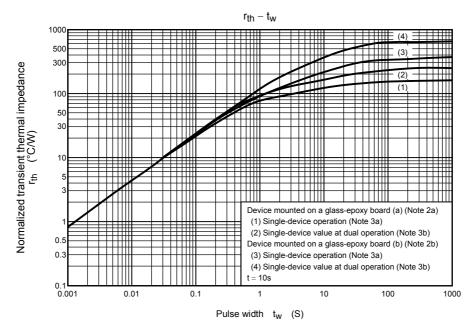




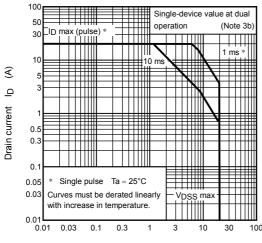












Drain-source voltage  $V_{DS}$  (V)

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